

CMOS Delay-3 (H.3)

Logical Effort Applications

20160919

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Based on

Uyemura

Introduction to VLSI Circuits and Systems

Weste

CMOS VLSI Design

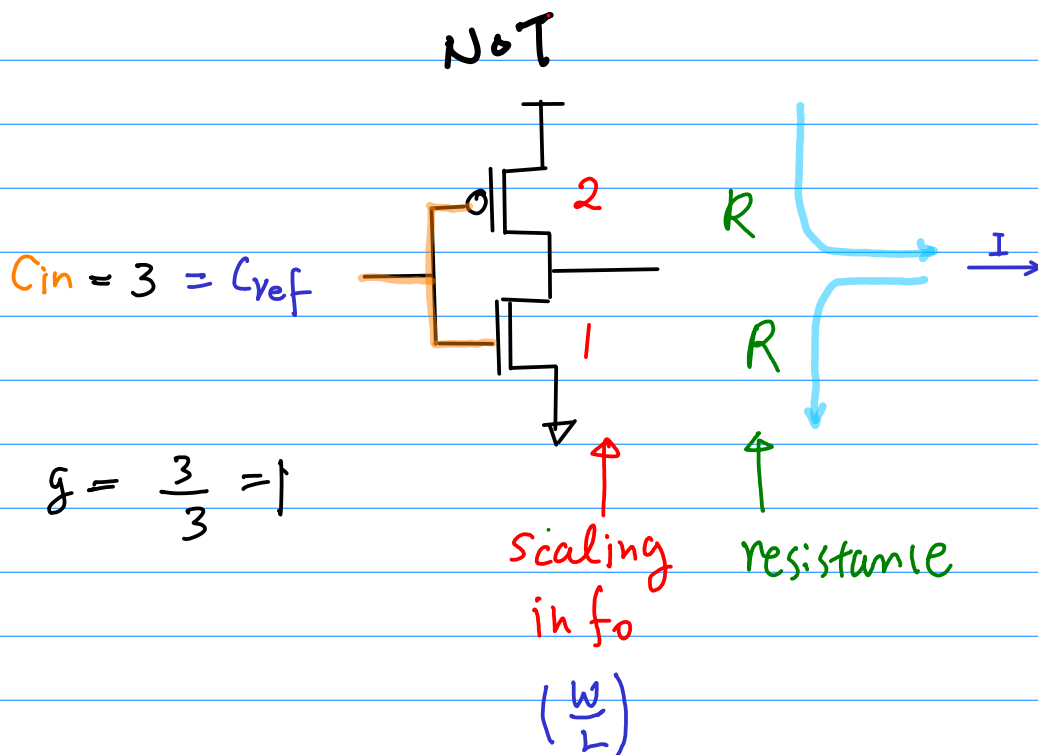
for 1X Inverter

$$\begin{aligned}
 C_{in} &= C_{ox} (W_n L + W_p L) \\
 &= C_{ox} (W_n L + r W_n L) \\
 &= C_{ox} W_n L (1 + r) \\
 &= C_{gn} (1 + r) = C_{ref}
 \end{aligned}$$

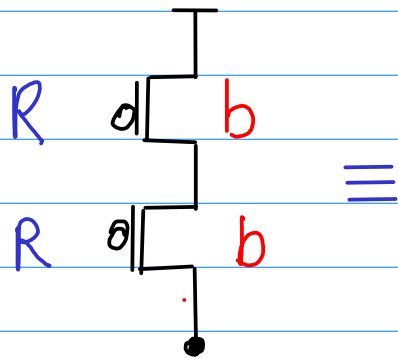
$$r = \hat{2} \sim 3$$

$$g = \frac{C_{in}}{C_{ref}} = \frac{C_{ref}}{C_{ref}} = 1$$

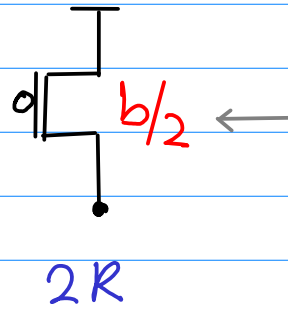
Comparing the performance of other gates



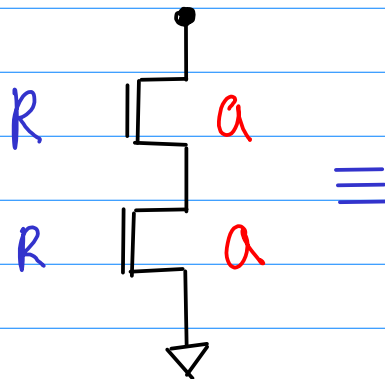
Series Connection



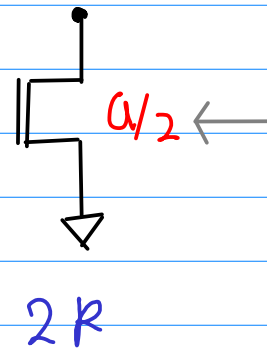
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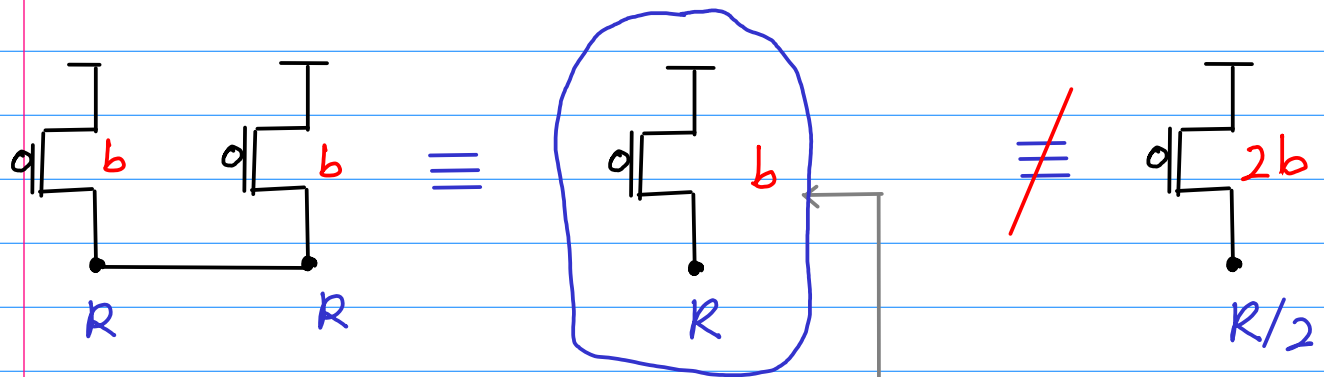
$$b = r a$$



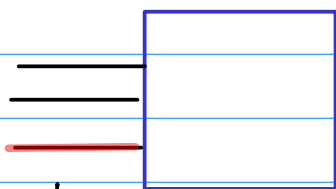
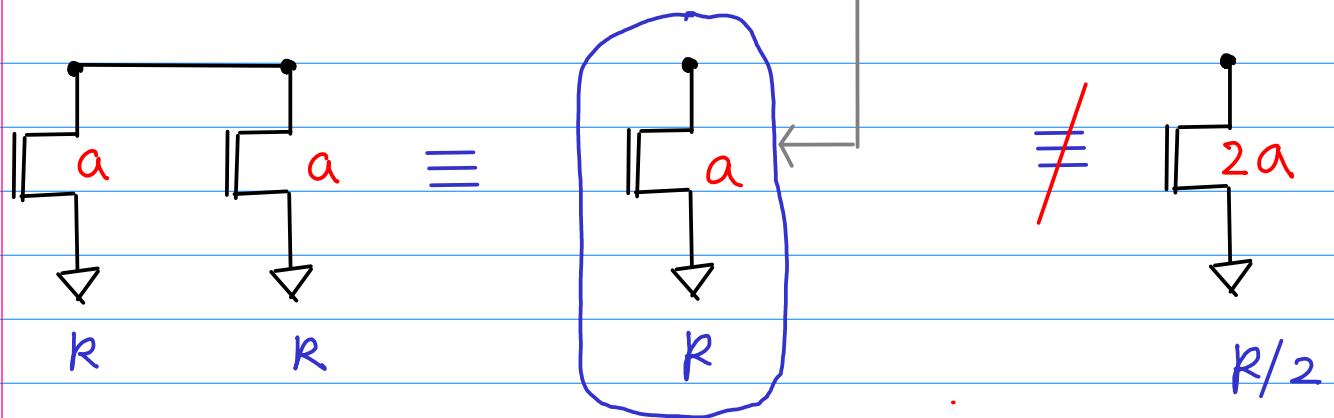
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Parallel Connection

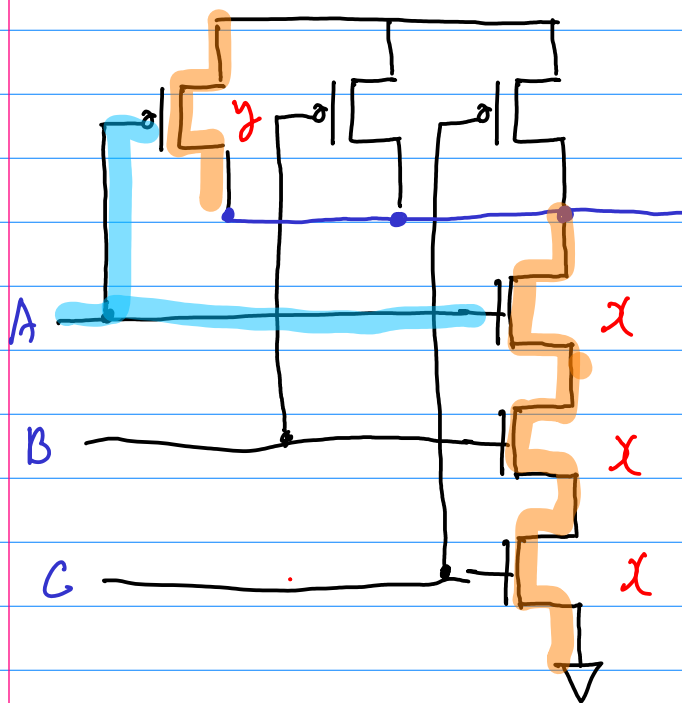


$$b = r a$$



considering only one input at a time

NAND $A_0 \equiv \text{D0-}$



① goal

$$\Rightarrow R \Rightarrow I$$

for the same output current

of the ref inverter

$$\Rightarrow R \Rightarrow I$$

for the same output current

of the ref inverter

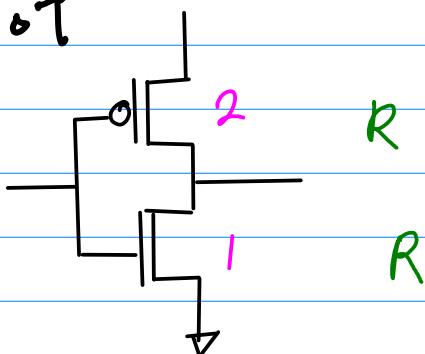
② Find Scaling info

$$R : \frac{1}{y} = \frac{1}{2} \quad y = 2$$

$$R : \frac{1}{x} + \frac{1}{x} + \frac{1}{x} = \frac{1}{1} \quad \frac{3}{x} = 1 \quad x = 3$$

* reference gate

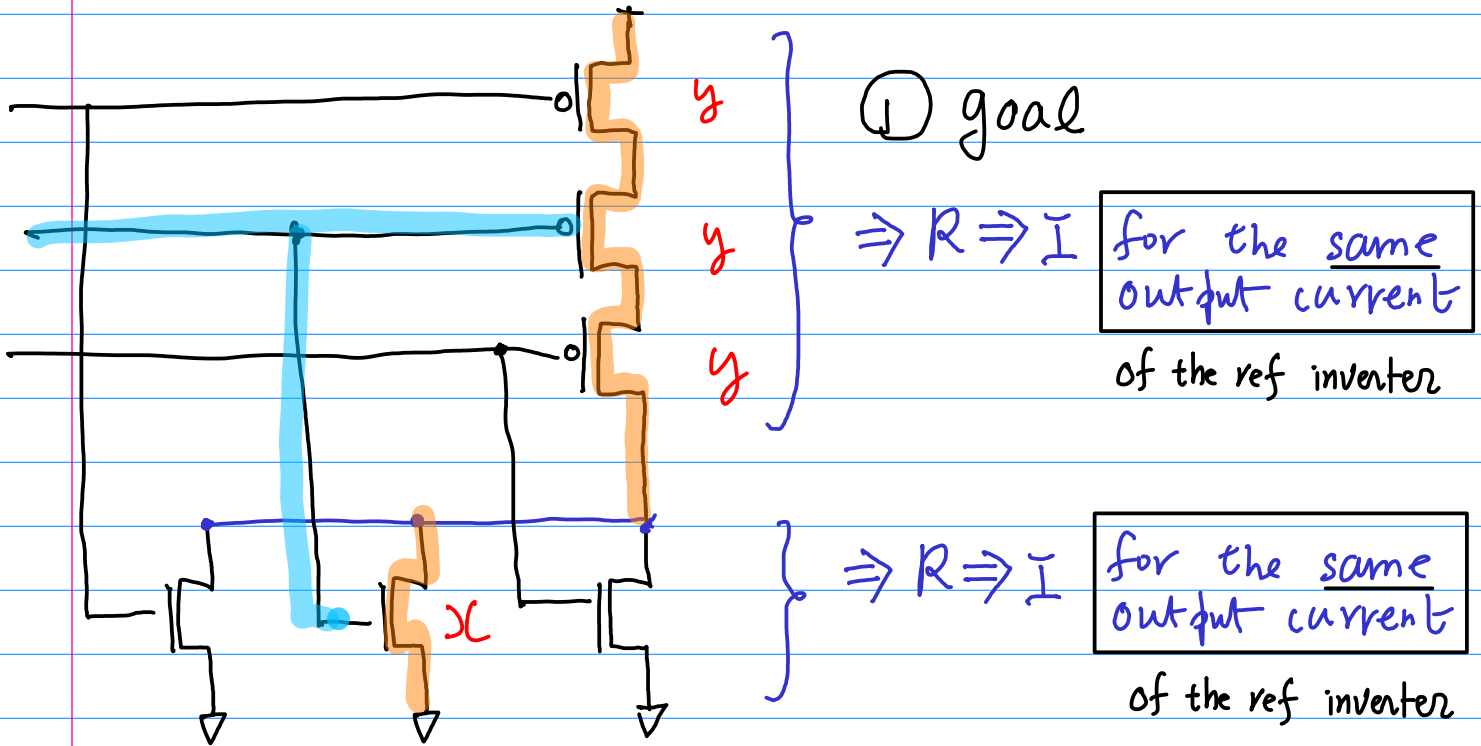
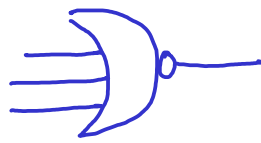
NOT



③ Compute $C_{in} = 2 + 3 = 5$
(Count $x+y$ in any input)

$$④ \quad g = \frac{C_{in}}{C_{ref}} = \frac{2+3}{2+1} = \frac{5}{3}$$

NOR

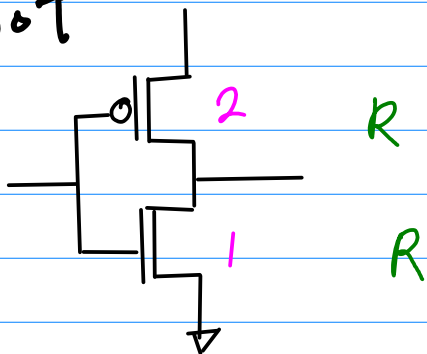


② Find Scaling info $R : \frac{3}{y} = \frac{1}{2} \quad y = 6$

$R : \frac{1}{x} = \frac{1}{1} \quad x = 1$

* reference gate

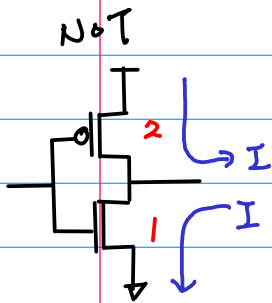
NOT



③ Compute $C_{in} = 6 + 1 = 7$
(count $x+y$ in any input)

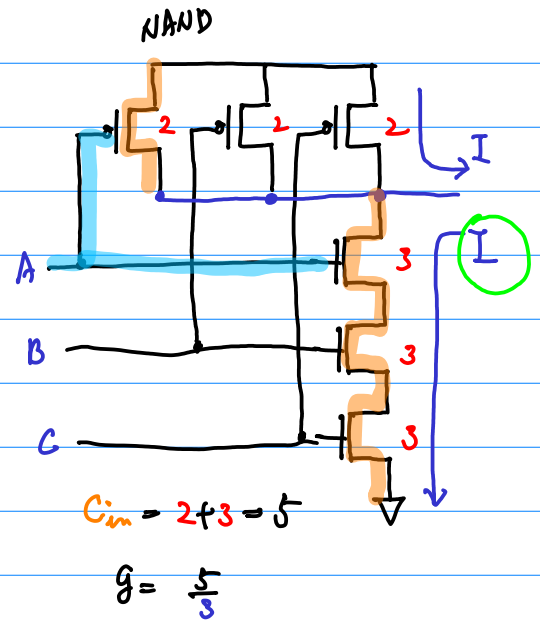
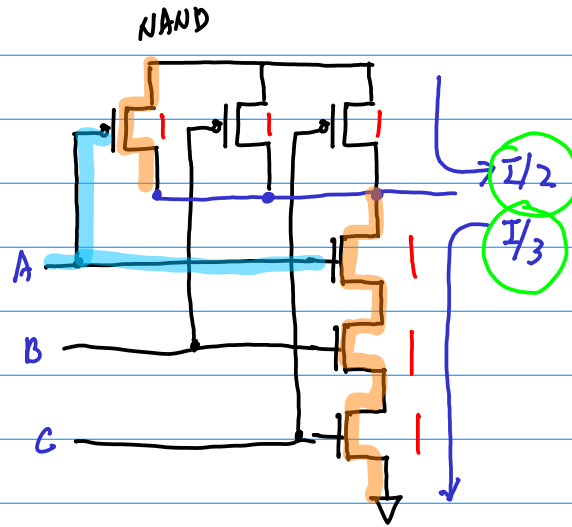
④
$$g = \frac{C_{in}}{C_{ref}} = \frac{6+1}{2+1} = \frac{7}{3}$$

Logical Effort (9) : Topological Effect



$$C_{in} = 3 = C_{ref}$$

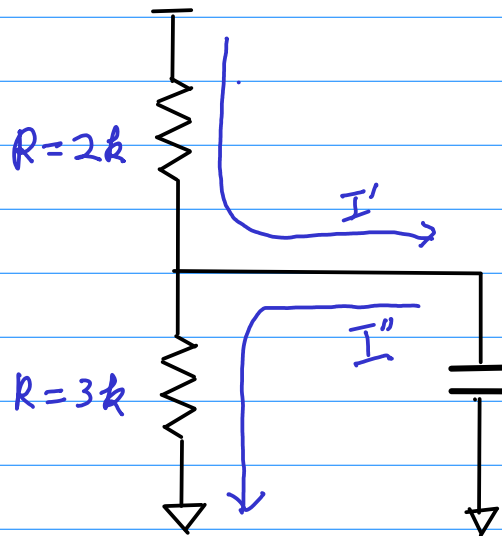
$$g = \frac{3}{3} = 1$$



Without proper sizing,

(pMOS's $R' = 2m$
nMOS's $R'' = 3m$)

(pMOS's $I' = I/2$
nMOS's $I'' = I/3$)



to get I ,

pMOS enlarged by a factor of 2

nMOS enlarged by a factor of 3

$$t_f \propto RC$$

$$t_f \propto 3$$

$$t_r \propto RC$$

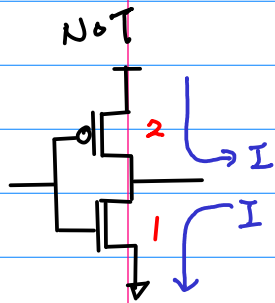
$$t_r \propto 2$$

$$t_{avg} = \frac{t_f + t_r}{2} \propto (3+2)$$

$$t_f + t_r \propto (3+2)$$

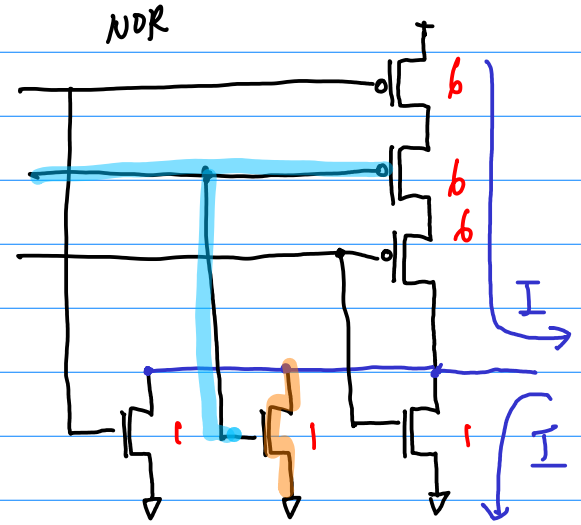
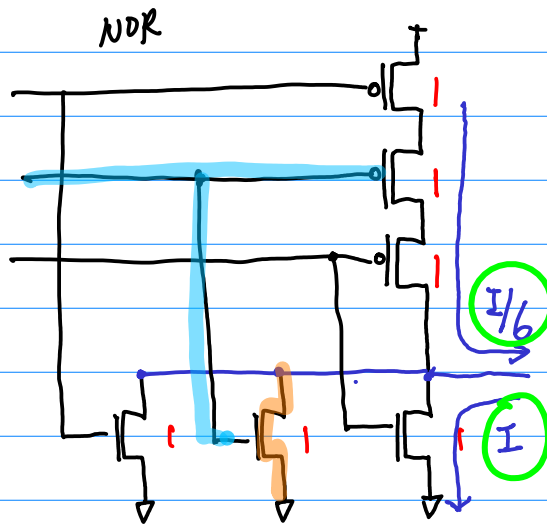
$$g = \frac{C_{in}}{C_{ref}} = \frac{t_{avg} \text{ of NAND}}{t_{avg} \text{ of NOT}}$$

Logical Effort (9) : Topological Effect



$$C_{in} = 3 = C_{ref}$$

$$g = \frac{3}{3} = 1$$



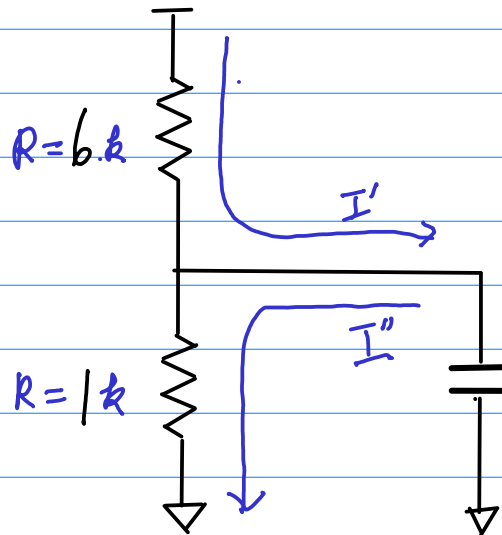
$$C_{in} = 6 + 1 = 7$$

$$g = \frac{7}{3}$$

Without proper sizing,

(pMOS's $R' = 6m$
nMOS's $R'' = 1m$)

(pMOS's $I' = I/6$
nMOS's $I'' = I$)



to get I ,
pMOS enlarged by a
factor of 6
nMOS enlarged by a
factor of 1

$$t_f \propto RC$$

$$t_r \propto RC$$

$$t_f \propto 1$$

$$t_r \propto 6$$

$$t_{avg} = \frac{t_f + t_r}{2} \propto (1 + 6)$$

$$t_f + t_r \propto (1 + 6)$$

$$g = \frac{C_{in}}{C_{ref}} = \frac{t_{avg} \text{ of NOR}}{t_{avg} \text{ of NOT}}$$

Electrical Effort (h) : Fan Out Load

Electrical Effort : the output & input cap ratio

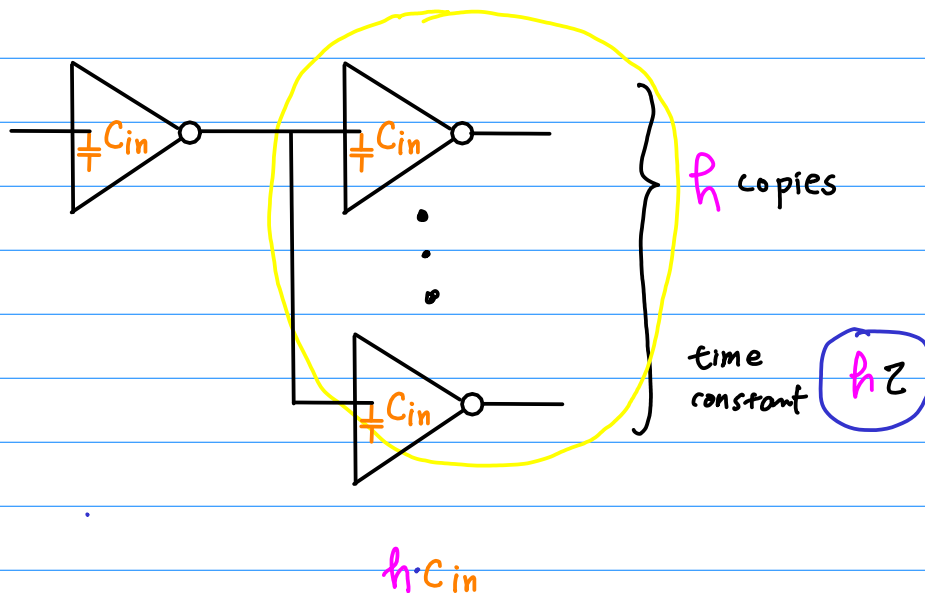
$$h = \frac{C_{out}}{C_{in}}$$

the ratio of the drive strength to drive C_{out} to the drive strength to drive its own capacitance C_{in}

C_{out} is h times larger than C_{in}

$$C_{out} = h C_{in}$$

h copies of the same gate



Parasitic Delay P

- delay due to internal
parasitic capacitance

sC_p

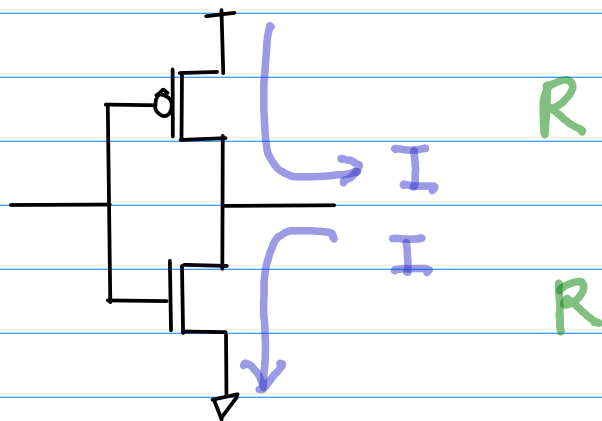
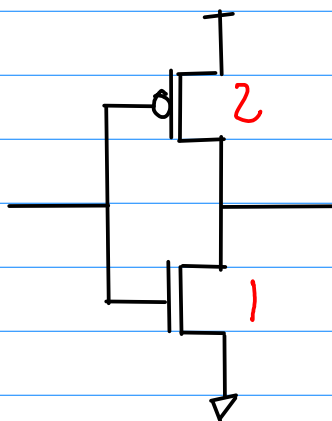
- excluding external load cap

C_{out}

- count only diffusion capacitance of the output

- delay without output load

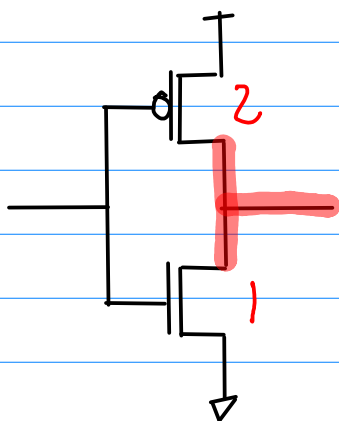
$$P = \left(\frac{C_{p,ref}}{C_{ref}} \right) = \left(\frac{\text{internal diffusion cap.}}{\text{gate cap of ref inv}} \right) = \frac{Z_{par}}{Z_{ref}}$$



②, ①: scaling info in order for PUN & PDN
to have the same R , I

$$\tau_{\text{ref}} = R \cdot C_{\text{in}} = R_{\text{ref}} \cdot C_{\text{ref}} = R \cdot 3C = 3RC$$

$$\tau_{\text{inv}} = R_{\text{ref}} \cdot C_{p,\text{ref}} = R \cdot 3C = 3RC$$




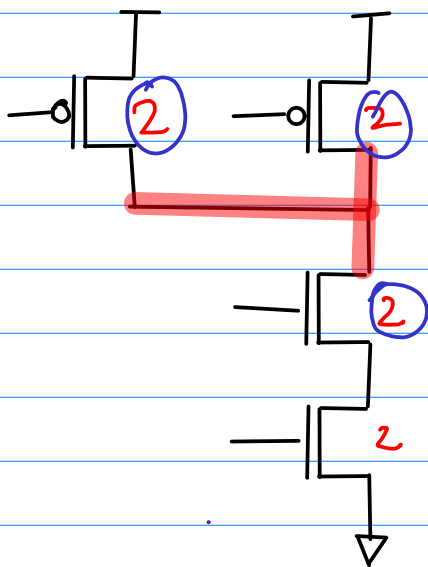
$C_{p,\text{ref}} \Rightarrow$ count scaling factors
connected to
the output

$$C_{p,\text{ref}} = 2 + 1 = 3$$

$$P = \left(\frac{C_{p,ref}}{C_{ref}} \right) = \left(\frac{\text{internal diffusion cap.}}{\text{gate cap of ref inv}} \right) = \frac{Z_{par}}{Z_{ref}}$$

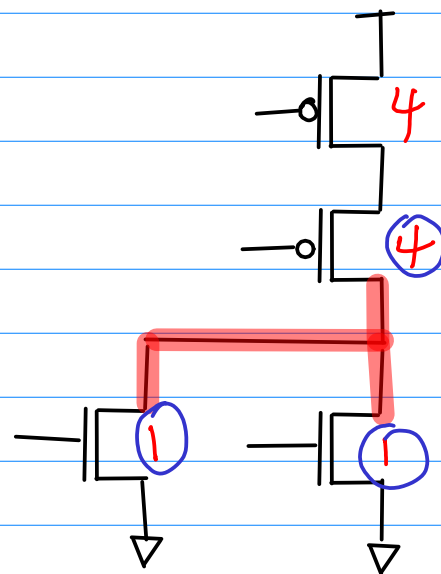
$$P = \frac{Z_{par}}{Z_{ref}} = \frac{R_{ref} \cdot C_{p,ref}}{R_{ref} \cdot C_{ref}}$$


 C_{in} of the reference inverter
 (Symmetric inverter)



$$(2) + (2) + (2) = 6$$

$$P_{NAND2} = \frac{6}{3} = 2$$



$$(4) + (1) + (1) = 6$$

$$P_{NOR2} = \frac{6}{3} = 2$$

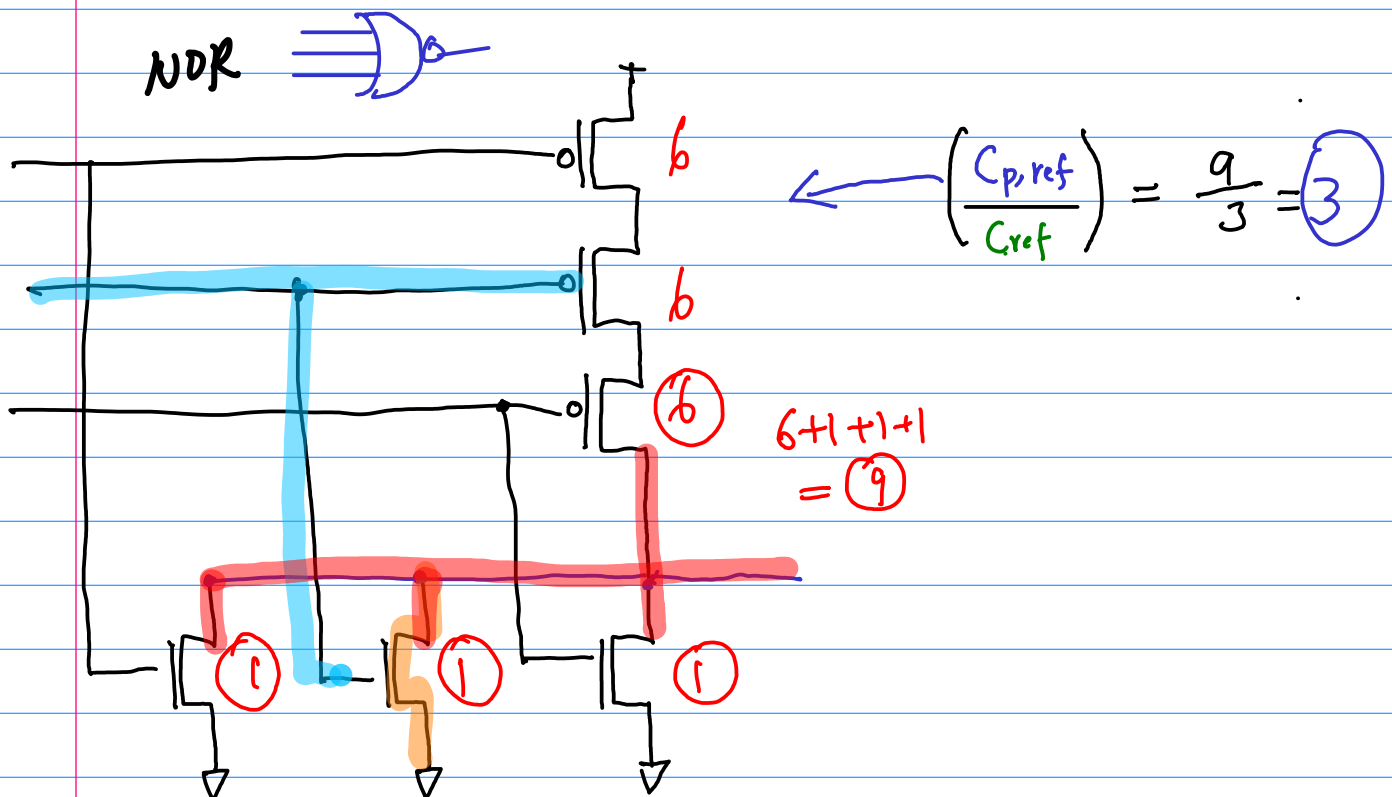
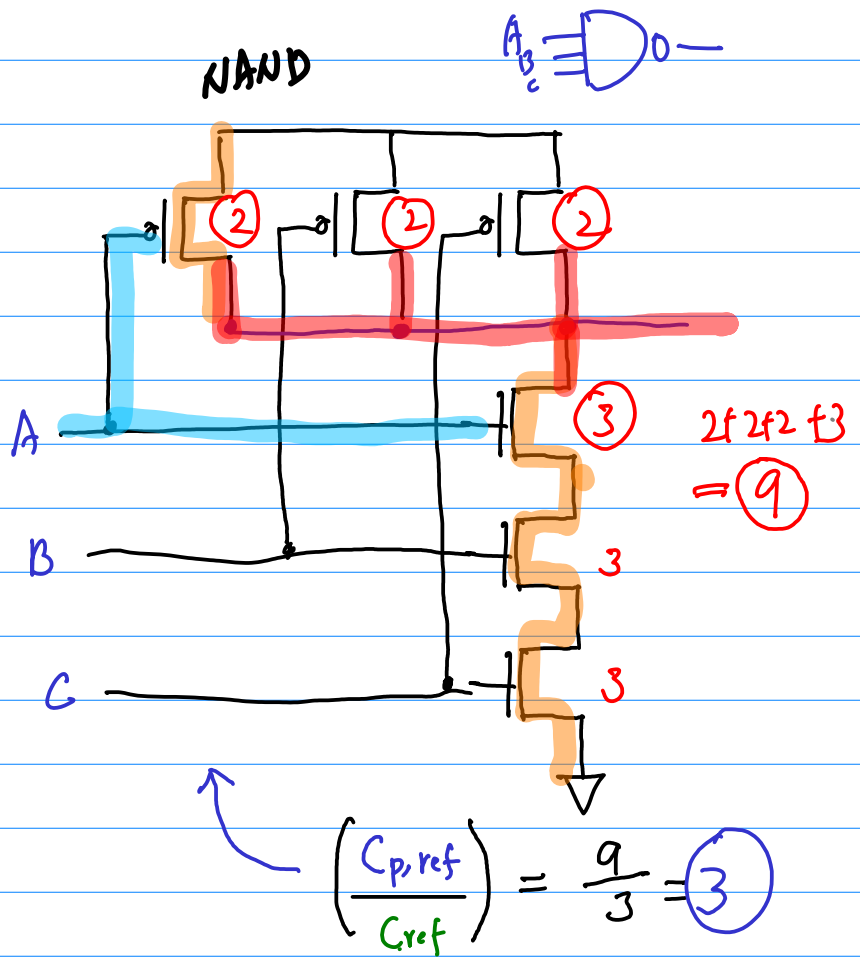
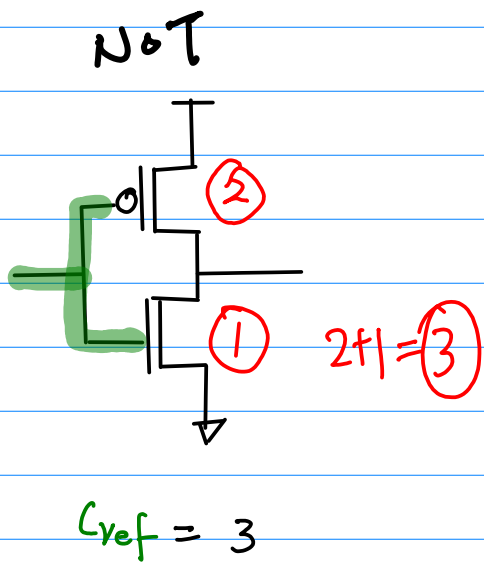
$$P = \frac{Z_{par}}{Z_{ref}} = \frac{R_{ref} \cdot C_{p,ref}}{R_{ref} \cdot \hat{C}_{ref}}$$



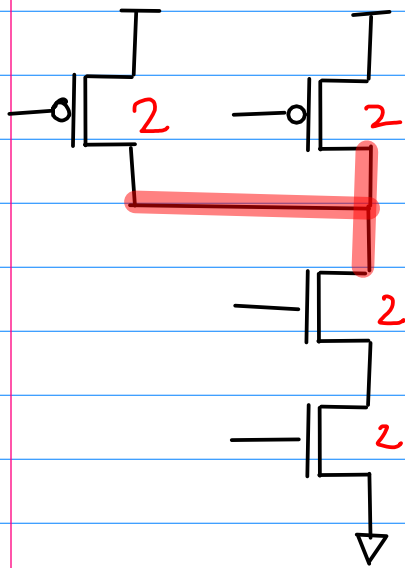
\hat{C}_{in} of the reference inverter
(Symmetric inverter)

$$P = \frac{1}{3} \left(\sum \text{Output scaling factors} \right)$$

Parasitic Delay



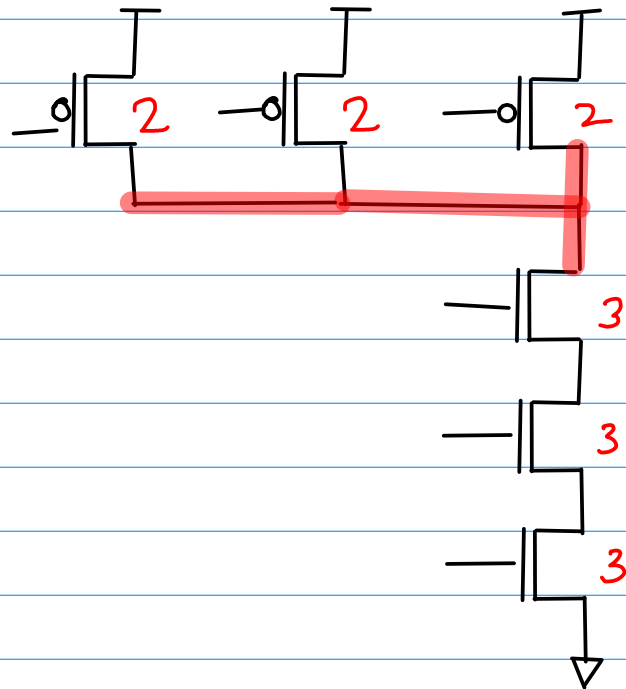
① NAND2



$$2 + (2 + 2) = 2(1 + 2)$$

$$\frac{2 \cdot 3}{3} = 2$$

NAND3



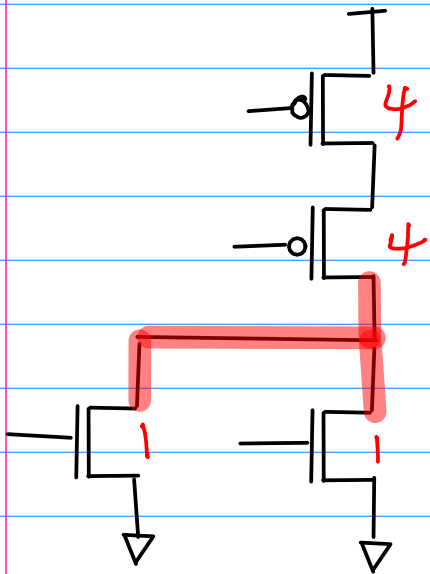
$$3 + (2 + 2 + 2) = 3(1 + 2)$$

$$\frac{3 \cdot 3}{3} = 3$$

①

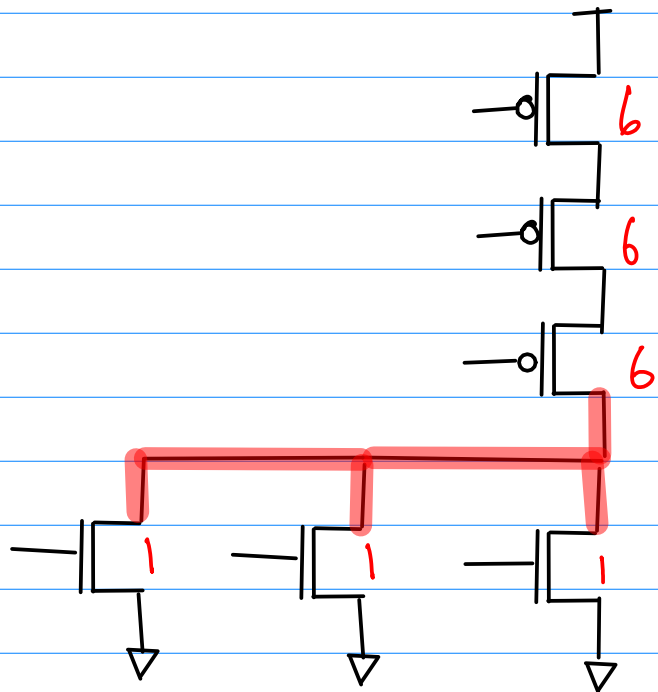
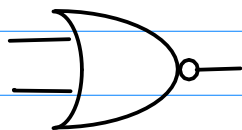
NOR₂

NOR₃



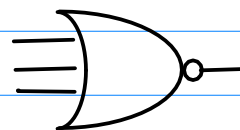
$$4 + 1 + 1 = 2 \cdot 2 + 2 \cdot 1 = 6$$

$$\frac{6}{3} = 2$$

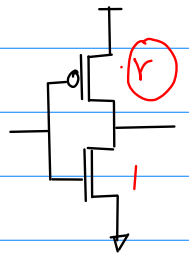
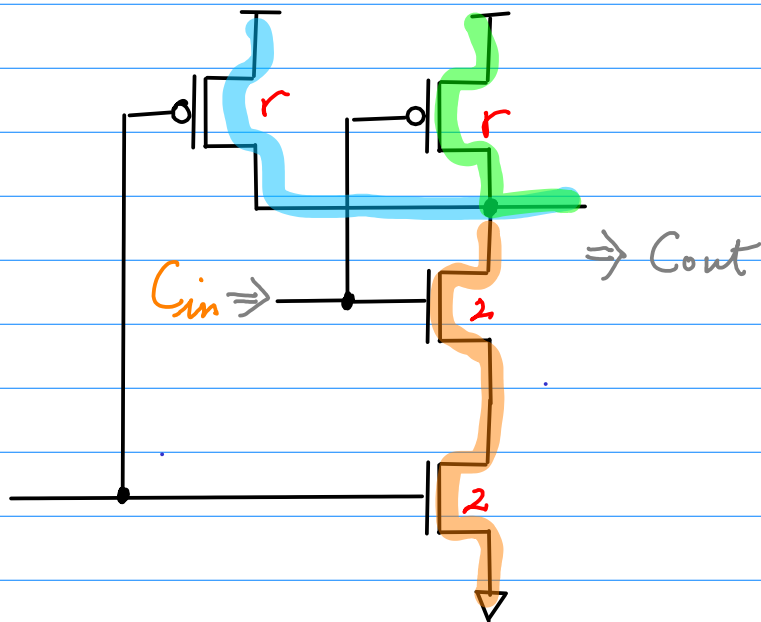


$$6 + 6 + 6 + 1 + 1 + 1 = 3 \cdot 2 + 3 \cdot 1 = 3(2 + 1) = 9$$

$$\frac{9}{3} = 3$$



Symmetric NAND2 (8)



$$K = \frac{1}{2} + \frac{1}{2} = 1$$

PMOS size r

⇐ the worst case path from V_{DD} to V_{out} is the same as the reference inverter

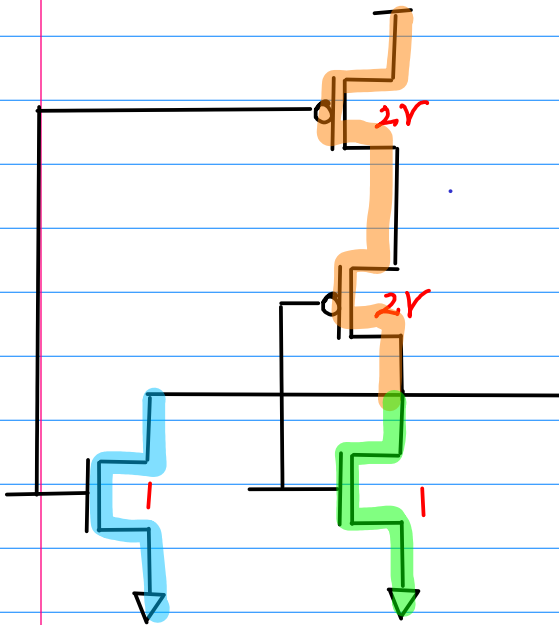
nMOS size (2)

⇐ the worst case path from CND to V_{out} must be twice as large as the inverter (series connection)

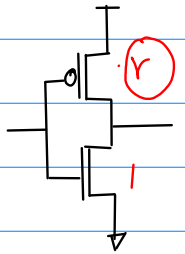
$$C_{in} = C_{Gn} (2 + r)$$

$$g = \frac{C_{in}}{C_{ref}} = \frac{C_{Gn}(2+r)}{C_{Gn}(1+r)} = \frac{2+r}{1+r}$$

Symmetric NOR2 (9)



$$R = \frac{1}{2r} + \frac{1}{2r} = \frac{1}{r}$$



PMOS size $2r$

⚡ the worst case path from V_{DD} to V_{out} must be twice as the inverter

(series connection)

nMOS size (1)

⚡ the worst case path from GND to V_{out} must be the same as as the inverter

$$C_{in} = C_{Gn} (1 + 2r)$$

$$g = \frac{C_{in}}{C_{ref}} = \frac{C_{Gn}(1+2r)}{C_{Gn}(1+r)} = \frac{1+2r}{1+r}$$

n -input NAND, NOR (9)

NAND₂

$$g = \frac{2+r}{1+r}$$

NOR₂

$$g = \frac{1+2r}{1+r}$$

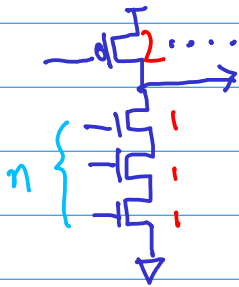
n -input NAND

$$g = \frac{n+r}{1+r}$$

n -input NOR

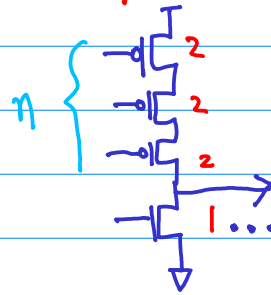
$$g = \frac{1+nr}{1+r}$$

n -input NAND



$$(1 \cdot n + 2)$$

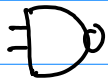
n -input NOR



$$(1 + 2 \cdot n)$$

Logical Effort (g)

2



$$\frac{4}{3} = \frac{(2+2)}{(1+2)}$$

3



$$\frac{5}{3} = \frac{(3+2)}{(1+2)}$$

4

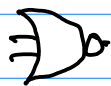


$$\frac{6}{3} = \frac{(4+2)}{(1+2)}$$

n



$$\frac{(n+2)}{(1+2)}$$



$$\frac{5}{3} = \frac{(1+2 \cdot 2)}{(1+2)}$$



$$\frac{7}{3} = \frac{(1+2 \cdot 3)}{(1+2)}$$



$$\frac{9}{3} = \frac{(1+2 \cdot 4)}{(1+2)}$$



$$\frac{(1+2 \cdot n)}{(1+2)}$$



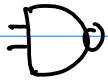
$$g = \frac{(n+r)}{(1+r)}$$



$$g = \frac{(1+r \cdot n)}{(1+r)}$$

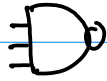
Parasitic delay (P)

2



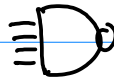
$$\frac{6}{3} = \frac{2(1+2)}{(1+2)}$$

3



$$\frac{9}{3} = \frac{3(1+2)}{(1+2)}$$

4



$$\frac{12}{3} = \frac{4(1+2)}{(1+2)}$$

n



$$\frac{n(1+2)}{(1+2)} = n$$



$$\frac{6}{3} = \frac{2(1+2)}{(1+2)}$$



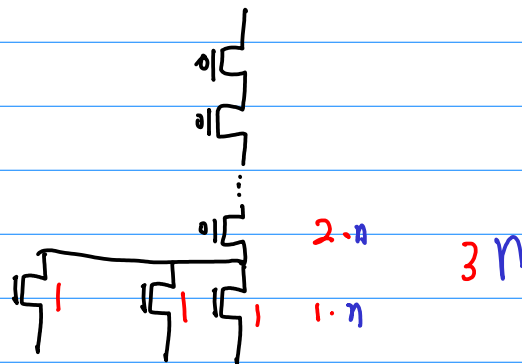
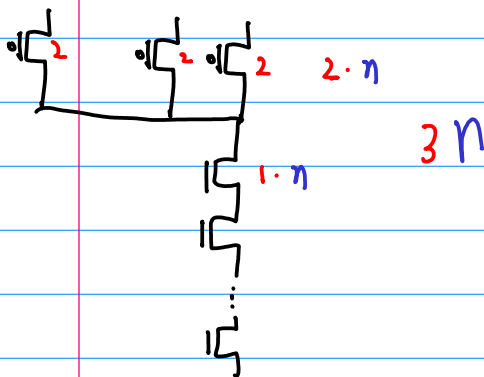
$$\frac{9}{3} = \frac{3(1+2)}{(1+2)}$$



$$\frac{12}{3} = \frac{4(1+2)}{(1+2)}$$



$$\frac{n(1+2)}{(1+2)} = n$$



① Logical Effort for the Same R (the same I)

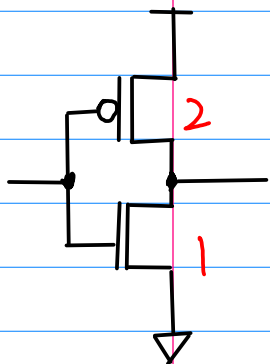
* Fixed output R

② Logical Effort for the Same C_{in}

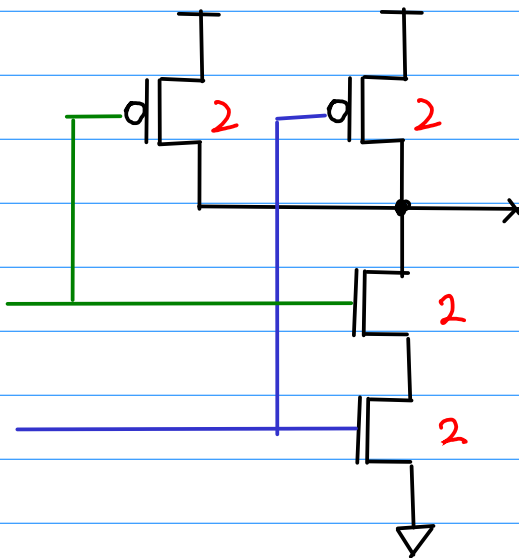
* Fixed Input C

①

Fixed output R

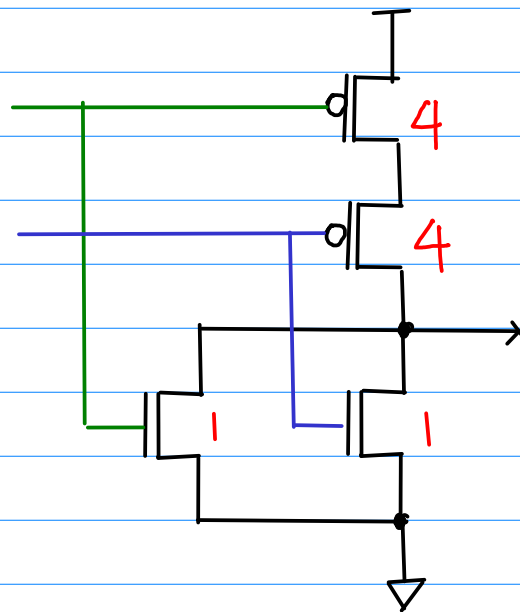


$$C_{in} = C_{ref} = 3$$



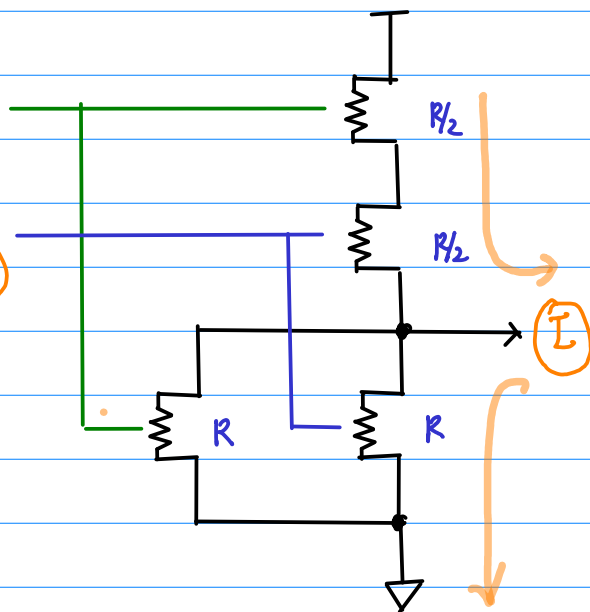
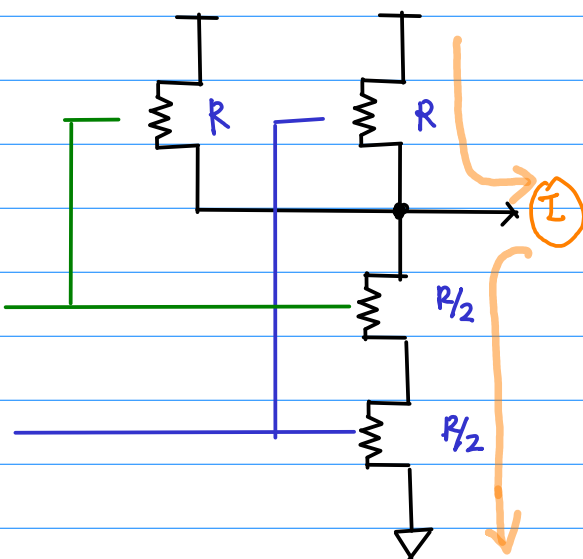
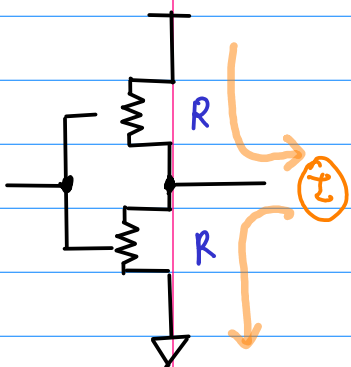
$$C_{in} = 4$$

$$g = \frac{4}{3}$$



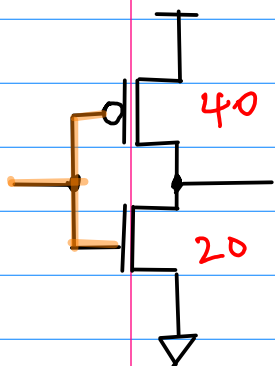
$$C_{in} = 5$$

$$g = \frac{5}{3}$$

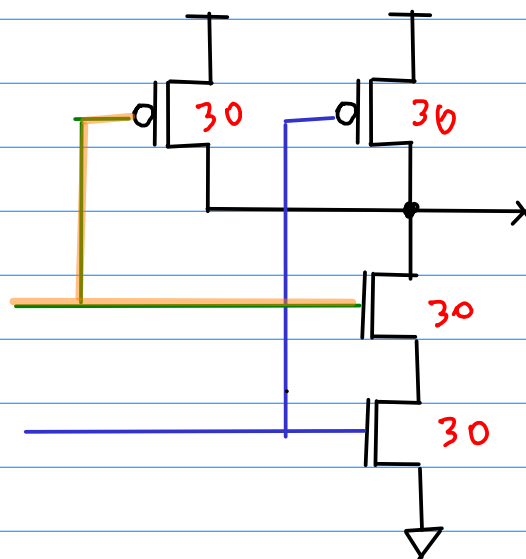


2

Fixed Input C



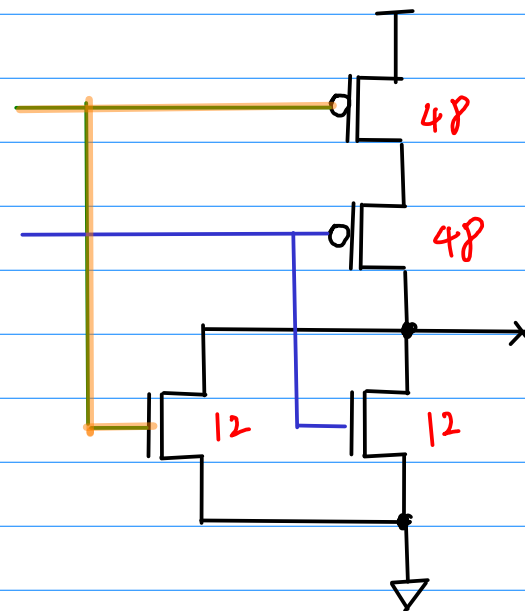
$$C_{in} = 60$$



$$C_{in} = 60$$

$$40 : I = 30 : I_1$$

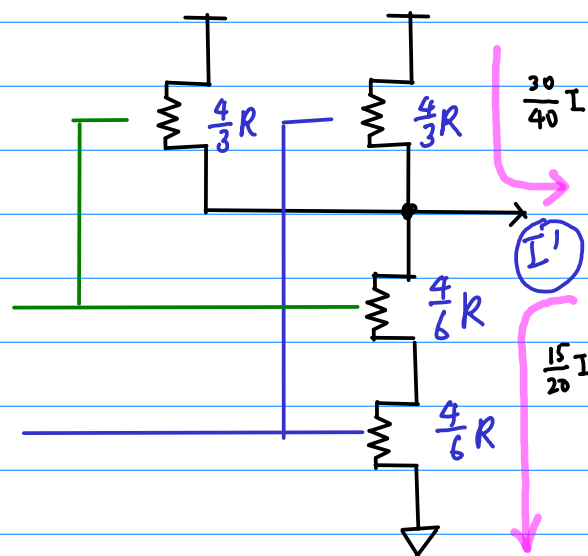
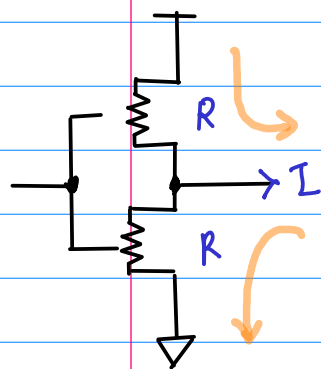
$$20 : I = 15 : I_2$$



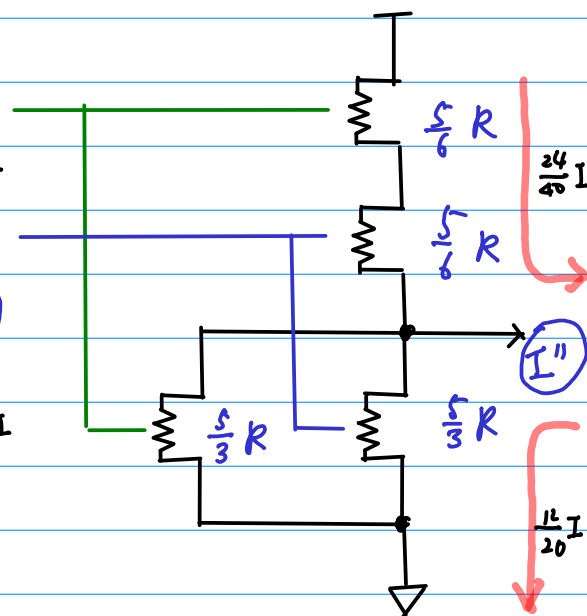
$$C_{in} = 60$$

$$40 : I = 24 : I_1''$$

$$20 : I = 12 : I_2''$$



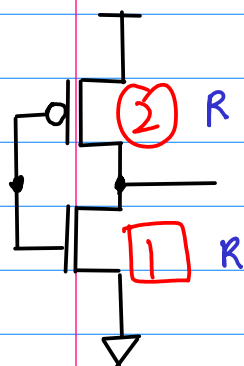
$$g = \frac{I}{I_1'} = \frac{4}{3}$$



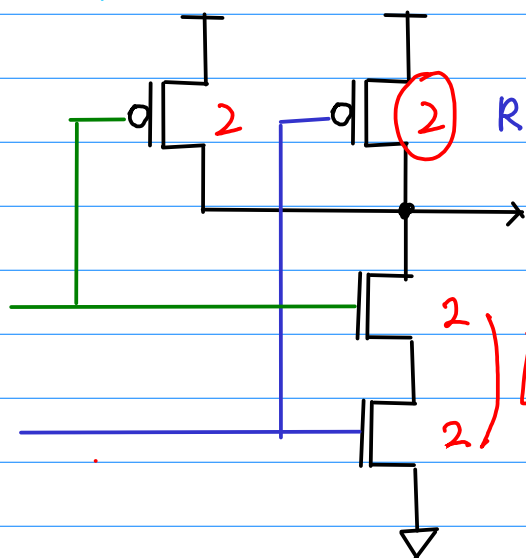
$$g = \frac{I}{I_1''} = \frac{5}{3}$$

①

Fixed output R

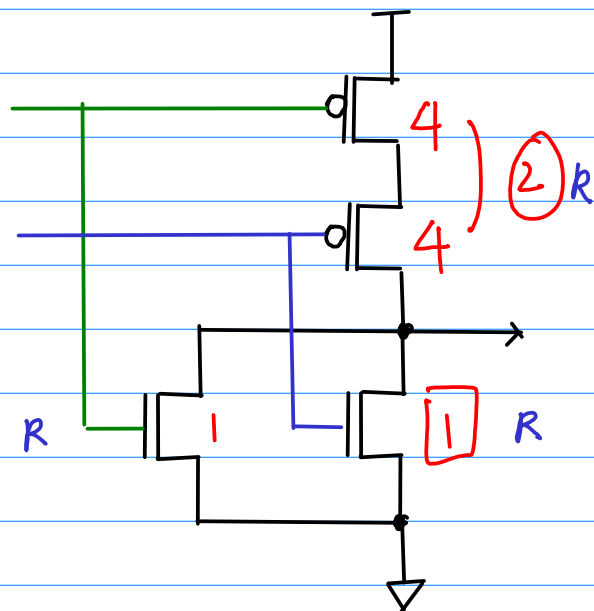


$$C_{in} = C_{ref} = 3$$



$$C_{in} = 4$$

$$g = \frac{4}{3}$$

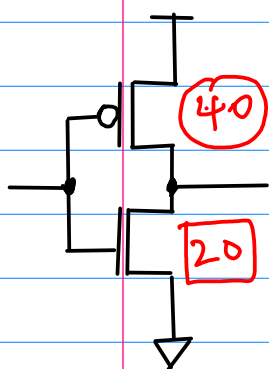


$$C_{in} = 5$$

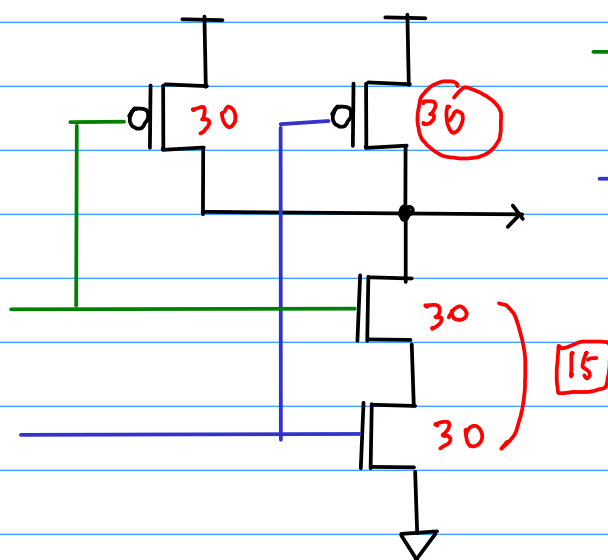
$$g = \frac{5}{3}$$

②

Fixed Input C

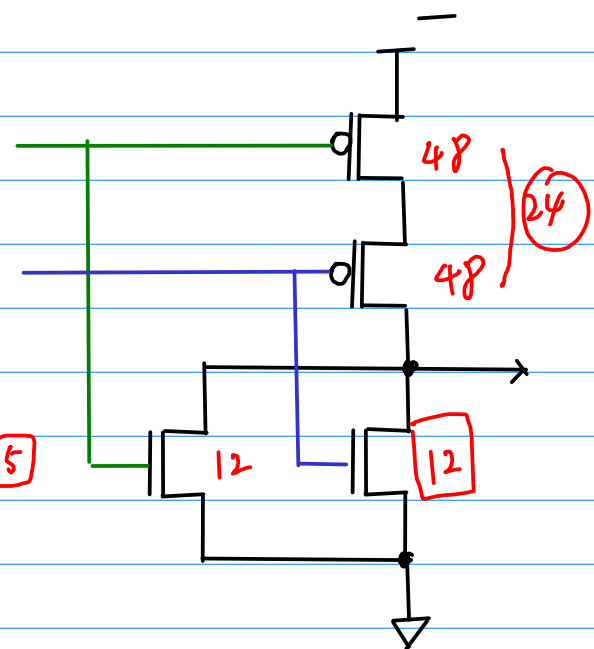


$$C_{in} = 60$$



$$C_{in} = 60$$

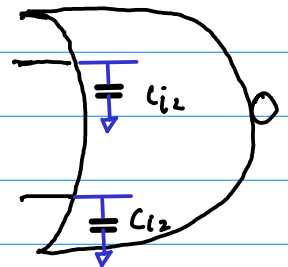
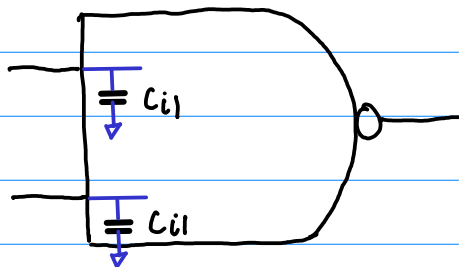
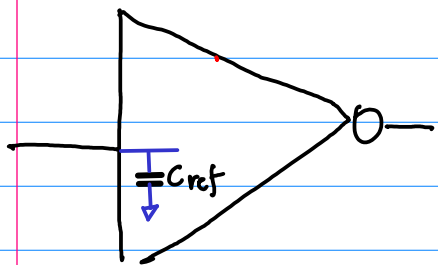
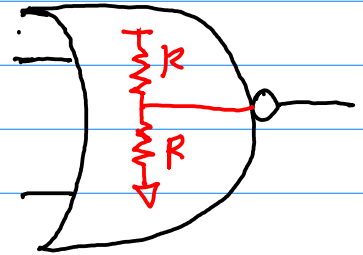
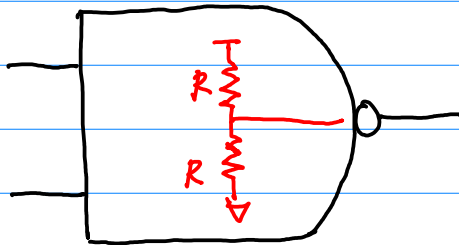
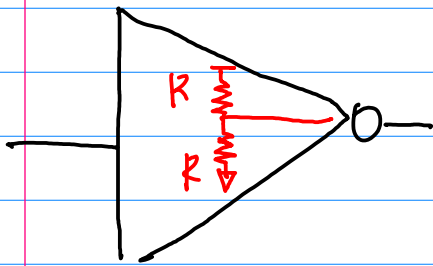
$$g = \frac{40}{30} = \frac{20}{15} = \frac{4}{3}$$



$$C_{in} = 60$$

$$g = \frac{40}{24} = \frac{20}{12} = \frac{5}{3}$$

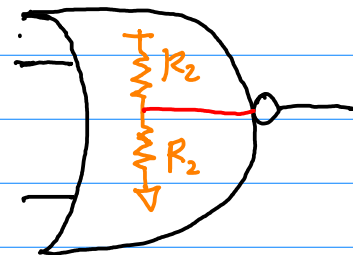
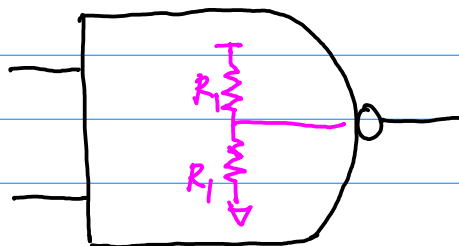
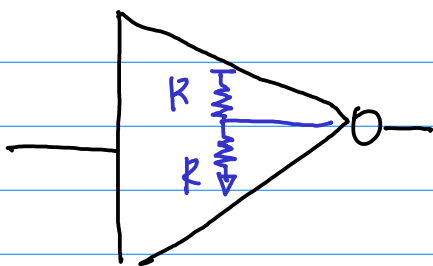
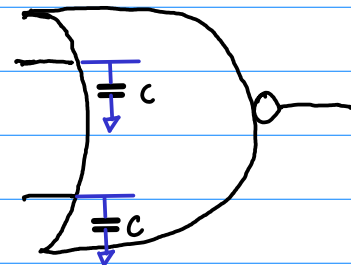
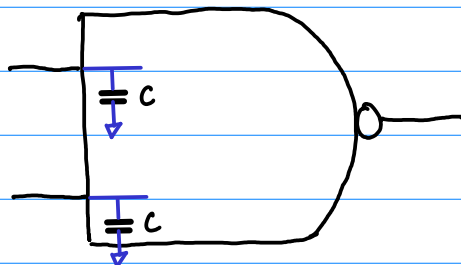
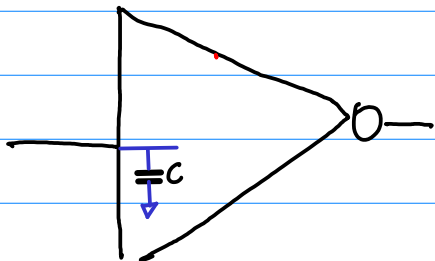
* Fixed output $R \rightarrow$ must increase size $\rightarrow C_{in} \uparrow$



$$g = \frac{C_{i1}}{C_{ref}}$$

$$g = \frac{C_{i2}}{C_{ref}}$$

* Fixed Input Cap \rightarrow Complexity of logic gate increase $R \uparrow$




$$g = \frac{R_1}{R}$$

$$g = \frac{R_2}{R}$$

* Fixed Output R

the same output I as that of 




more complex
topology than 

for the same I
the size must be increased.

$$\text{ratio } g = \frac{C_{in}}{C_{ref}}$$

* Fixed Input C



more complex
topology than 

the output current becomes smaller

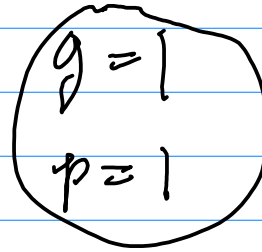
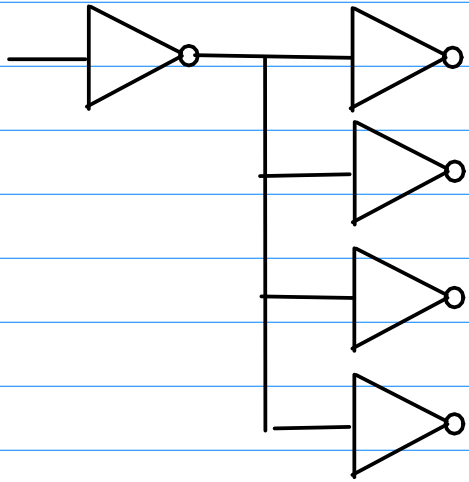
the output R becomes greater

$$\text{ratio } g = \frac{R}{R_{ref}}$$

Symmetric \Rightarrow

fall time = rise time

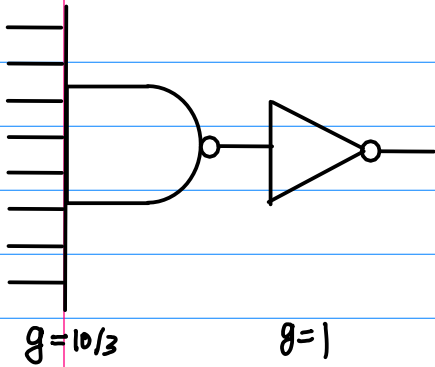
F04



$$g \cdot h + p = 1 \cdot h + 1 = h + 1$$

$$g_{NAND} = \frac{n + r}{1 + r}$$

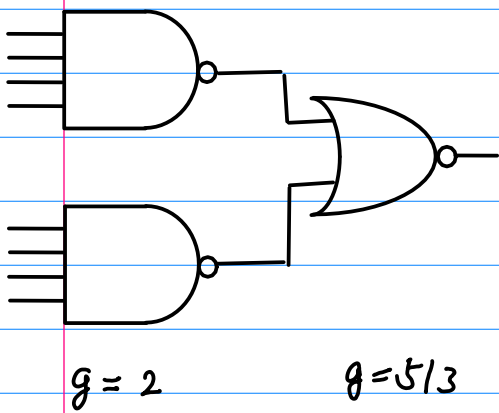
$$g_{NOR} = \frac{1 + nr}{1 + r}$$



$$\frac{8+2}{1+2} = \frac{10}{3}$$

$$\frac{1+2}{1+2} = 1$$

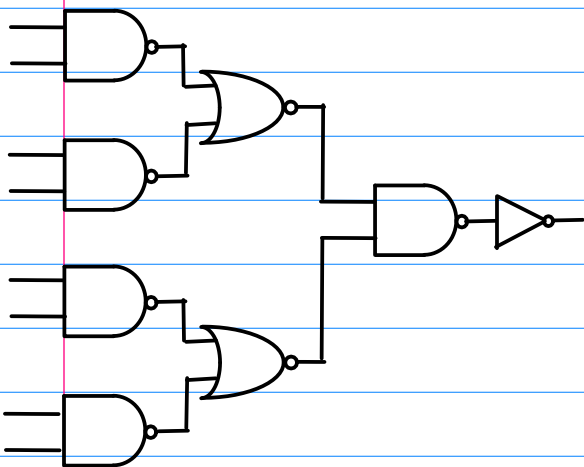
$$G = \frac{10}{3}$$



$$\frac{4+2}{1+2} = \frac{6}{3} = 2$$

$$\frac{1+2 \cdot 2}{1+2} = \frac{5}{3}$$

$$G = \frac{10}{3}$$



$$\frac{2+2}{1+2} = \frac{4}{3}$$

$$\frac{1+2 \cdot 2}{1+2} = \frac{5}{3}$$

$$g = 4/3 \quad g = 5/3 \quad g = 4/3 \quad g = 1$$

$$G = \frac{4}{3} \times \frac{5}{3} \times \frac{4}{3} = \frac{80}{27}$$